



TEST REPORT

No. 2009TAR105

for

ZTE CORPORATION

HSDPA Mini PCI Express Card

Model Name: MF200

with

Hardware Version: P678A2-2.0.0

Software Version: BD_P678A2V1.0.0B01

Issued Date: Sep 3th, 2009

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of TMC Beijing.

Test Laboratory:

DAR accreditation (DIN EN ISO/IEC 17025): No. DAT-P-114/01-01

FCC 2.948 Listed: No.733176

IC O.A.T.S listed: No.6629A-1

TMC Beijing, Telecommunication Metrology Center of Ministry of Industry and Information Technology

No. 52, Huayuan Bei Road, Haidian District, Beijing, P. R. China 100083.

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1. Test Laboratory

1.1. Testing Location

Company Name: TMC Beijing, Telecommunication Metrology Center of MIIT
Address: No 52, Huayuan beilu, Haidian District, Beijing,P.R.China
Postal Code: 100083
Telephone: 00861062303288
Fax: 00861062304793

1.2. Testing Environment

Normal Temperature: 15-35°C
Relative Humidity: 20-75%

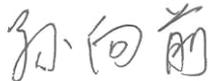
1.3. Project data

Testing Start Date: Aug 30th, 2009
Testing End Date: Aug 31th, 2009

1.4. Signature



Zi Xiaogang
(Prepared this test report)



Sun Xiangqian
(Reviewed this test report)



Lu Bingsong
Deputy Director of the laboratory
(Approved this test report)

2. Client Information

2.1. Applicant Information

Company Name: ZTE CORPORATION
Address /Post: ZTE Plaza, Keji Road South, Hi-Tech Industrial Park, Nanshan
District, Shenzhen, Guangdong, 518057, P.R.China
City: Shenzhen
Postal Code: 518057
Country: China
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Fax: 0086 21 61460600

2.2. Manufacturer Information

Company Name: ZTE CORPORATION
Address /Post: ZTE Plaza, Keji Road South, Hi-Tech Industrial Park, Nanshan
District, Shenzhen, Guangdong, 518057, P.R.China
City: Shenzhen
Postal Code: 518057
Country: China
Telephone: 0086 21 68895196
Fax: 0086 21 61460600

3. Equipment Under Test (EUT) and Ancillary Equipment (AE)

3.1. About EUT

Description	HSDPA Mini PCI Express Card
Model Name	MF200
FCC ID	Q78-ZTEMF200
Power supply	DC (PCI Port)

Note: Photographs of EUT are shown in ANNEX A of this test report. Components list, please refer to documents of the manufacturer; it is also included in the original test record of Telecommunication Metrology Center of MII of People's Republic of China.

3.2. Internal Identification of EUT used during the test

EUT ID*	SN or IMEI	HW Version	SW Version
N12	/	P678A2-2.0.0	BD_P678A2V1.0.0B01

4. Reference Documents

4.1. Reference Documents for testing

The following documents listed in this section are referred for testing.

Reference	Title	Version
FCC Part 15, Subpart B	Radio frequency devices	V 10.1.07
ANSI C63.4	Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz	2003

5. LABORATORY ENVIRONMENT

Semi-anechoic chamber (23 meters×17meters×10meters) did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 30 °C
Relative humidity	Min. = 30 %, Max. = 60 %
Shielding effectiveness	> 110 dB
Electrical insulation	> 10 kΩ
Ground system resistance	< 0.5 Ω
Normalised site attenuation (NSA)	< ±3.2 dB, 10 m distance, from 30 to 1000 MHz
Uniformity of field strength	Between 0 and 6 dB, from 80 to 2000 MHz

Control room did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 35 °C
Relative humidity	Min. =30 %, Max. = 60 %
Shielding effectiveness	> 110 dB
Electrical insulation	> 10 kΩ
Ground system resistance	< 0.5 Ω

Conducted chamber did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 30 °C
Relative humidity	Min. = 30 %, Max. = 60 %
Shielding effectiveness	> 110 dB
Electrical insulation	> 10 kΩ
Ground system resistance	< 0.5 Ω

Fully-anechoic chamber (6.8 meters×3.08 meters×3.53 meters) did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 30 °C
Relative humidity	Min. = 30 %, Max. = 60 %
Shielding effectiveness	> 110 dB
Electrical insulation	> 10 kΩ
Ground system resistance	< 0.5 Ω
Uniformity of field strength	Between 0 and 6 dB, from 80 to 2000 MHz

6. SUMMARY OF TEST RESULTS

Abbreviations used in this clause:	
P	Pass
NA	Not applicable
F	Fail

Clause	List	Clause in FCC rules	Verdict
1	Radiated Emission	15.109(a)	P
2	Conducted Emission	15.107(a)	P

7. Test Equipments Utilized

NO.	Description	TYPE	SERIES NUMBER	MANUFACTURER	CAL DUE DATE
1	Test Receiver	ESS	847151/015	R&S	2009-10-30
2	Test Receiver	ESI40	831564/002	R&S	2010-2-11
3	BiLog Antenna	3142B	9908-1403	EMCO	2010-1-16
4	BiLog Antenna	VUL9163	9163 175	Schwarzbeck	2009-9-19
5	Signal Generator	SMT06	831285/005	R&S	2009-12-26
6	Signal Generator	SMP04	100070	R&S	2010-4-20
7	LISN	ESH2-Z5	829991/012	R&S	2009-9-13
8	Spectrum Analyzer	FSU26	200030	R&S	2010-6-18
9	Universal Radio Communication Tester	CMU200	100680	R&S	2009-8-23

NO.	Description	TYPE	SERIES NUMBER	MANUFACTUR E	CAL DUE DATE
10	Dual-Ridge Waveguide Horn Antenna	3115	9906-5827	EMCO	2010-3
11	Dual-Ridge Waveguide Horn Antenna	3116	2663	EMCO	2010-3
12	Dual-Ridge Waveguide Horn Antenna	3116	2661	EMCO	2010-3
13	Climatic chamber	SH-241	92003546	ESPEC	2010-5-15

ANNEX A: MEASUREMENT RESULTS

A.1 Radiated Emission (§15.109(a))

A.1.1 Method of measurement

The field strength of radiated emissions from the unintentional radiator at a distance of 3 meters is tested. Tested in accordance with the procedures of ANSI C63.4 – 2003, section 8.3. The test set-up please refers to Annex C.1.

A.1.2 EUT Operating Mode:

During the EUT had been installed in the Notebook.

A.1.3 Measurement Limit

Frequency of emission (MHz)	Field strength (microvolts/meter)
30-88	100
88-216	150
216-960	200
Above 960	500

A.1.4 Measurement Results

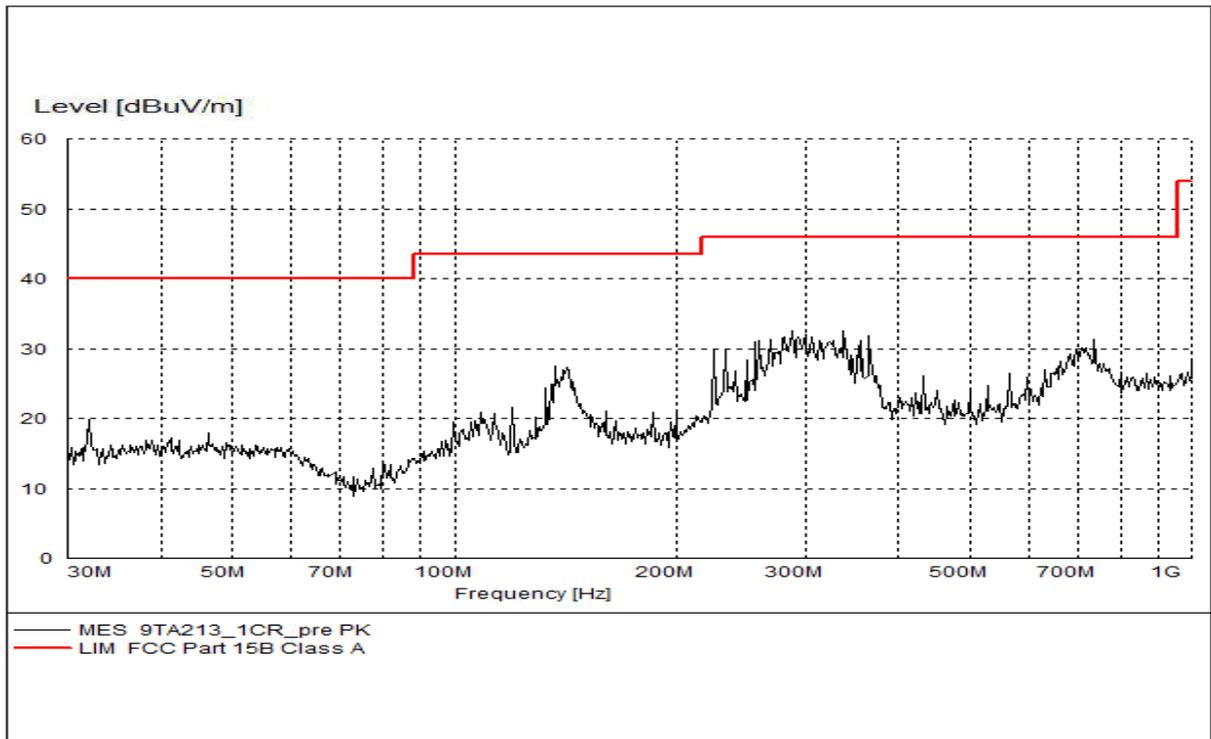


Figure A.1 Radiated Emission from 30MHz to 1GHz

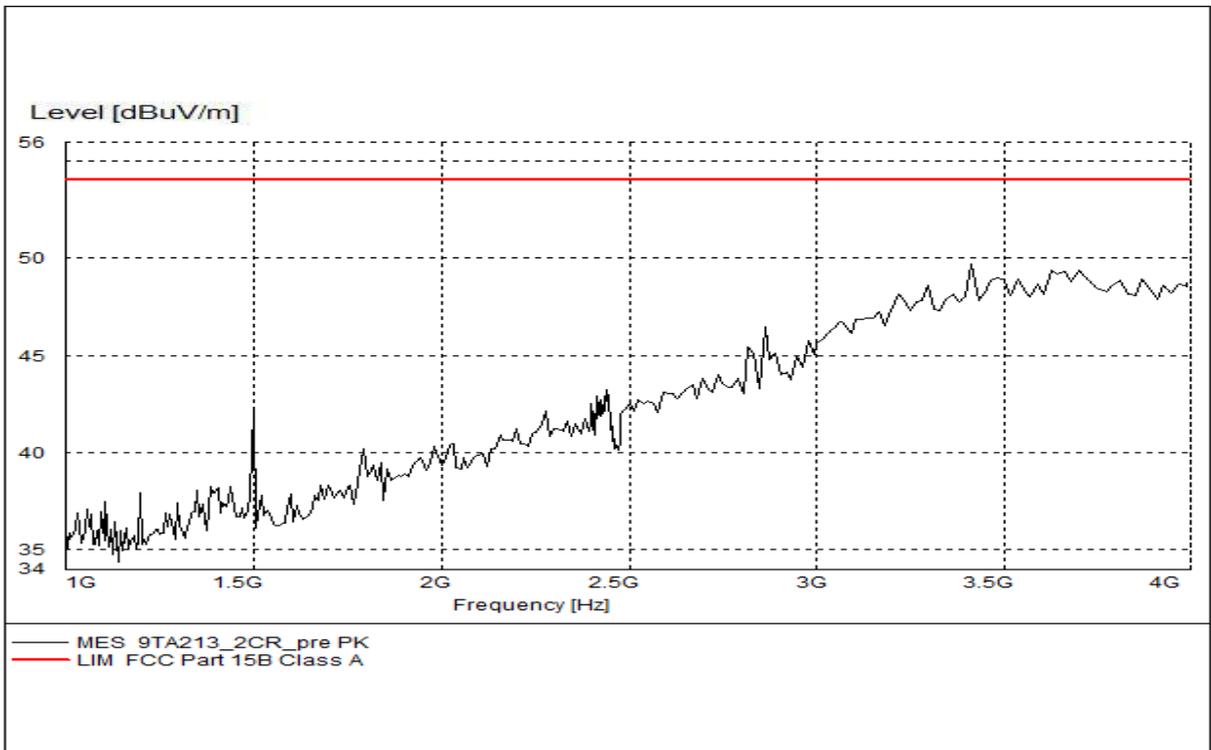


Figure A.2 Radiated Emission from 1GHz to 4GHz

A.2 Conducted Emission (§15.107(a))

A.2.1 Method of measurement

For equipment that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies within the band 150kHz to 30MHz shall not exceed the limits. Tested in accordance with the procedures of ANSI C63.4 – 2003, section 7.2. The test set-up please refers to Annex C.2.

A.2.2 EUT Operating Mode:

During the EUT had been installed in the Notebook.

A.2.3 Measurement Limit

Frequency of emission (MHz)	Conducted limit (dB μ V)	
	Quasi-peak	Average
0.15-0.5	66 to 56*	56 to 46*
0.5-5	56	46
5-30	60	50

*Decreases with the logarithm of the frequency

A.2.4 Test Condition in charging mode

Voltage (V)	Frequency (Hz)
110	60

A.2.4 Measurement Results

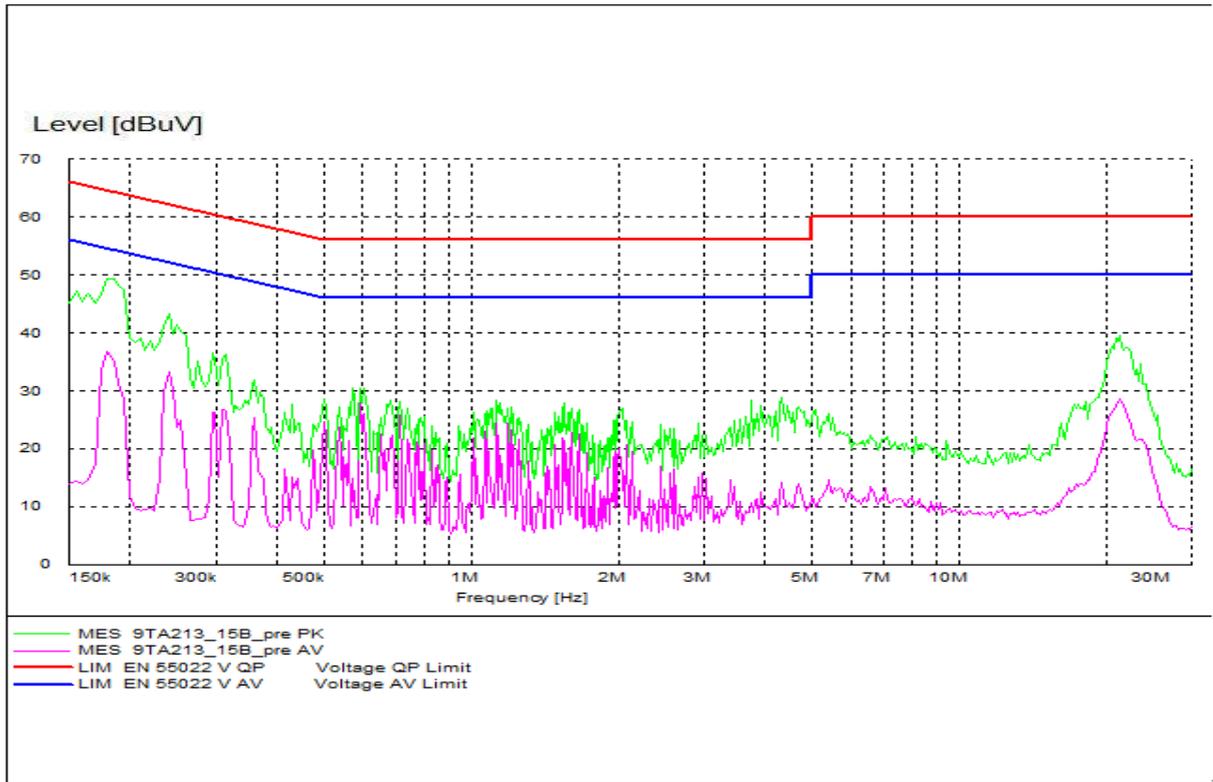


Figure A.3 Conducted Emission

END OF REPORT